Detailed Technical Specification of High Performance Sequential Wavelength Dispersive X-ray Fluorescence Spectrometer

High Performance Sequential Wavelength dispersive X-ray Fluorescence spectrometer with accessories. i.e.

- High Voltage generator ,4kW
- X-ray Tube: Rh anode, end window, thin Be(50 microns) window, 4.2kW
- Element Range B to U
- All analyzing crystal required for analysis of B to U
  - Analyzer Crystal LiF 220
  - Analyzer Crystal LiF 200
  - Analyzer Crystal PET
  - Analyzer Crystal XS-55
  - Analyzer Crystal XS-B
  - Analyzer Crystal XS-N
  - Analyzer Crystal TIAP
- Detectors: Scintillation and Gas Flow Proportional Counter
- Beam Path environment: Vacuum, Helium and Air
- Set of reference samples for Calibration
- Power supply: 220 V, Single Phase
- Chiller Unit as per the requirement of equipment
- UPS as per the load of equipment
- System software installed on computer
- Software based control for all functions of equipment.(hardware control, calibration and application development)
- Closed loop water circulation
- Goniometer with independent drive for θ and 2θ

1.	Angle range for 2θ	1-148°
2.	Angle range for θ	1-74°
3.	Scanning Speed	up to 10° 2θ/s
4.	Slew Rate	40° 2θ/s
5.	Angular reproducibility	0.0001° for both θ and 2θ
6.	Angular accuracy	0.0025° for both θ and 2θ
7.	Temperature stabilization	±0.05°C at 30° C

- Free of cost two week foreign training of hardware and software of equipment for two Scientist/Engineer
- Consumable Spare parts for Five Year

Make : M/s. Bruker / Equivalent

Required Quantity: 01 No.